

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination DE JONG ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0007459 A1	01-2003	Yi et al.	370/252
*	B	US-5,253,253	10-1993	Brame et al.	370/341
*	C	US-2002/0159410 A1	10-2002	Odenwalder et al.	370/329
*	D	US-2002/0191544 A1	12-2002	Cheng et al.	370/236
*	E	US-6,181,704 B1	01-2001	Drottar et al.	370/410
*	F	US-6,816,478 B1	11-2004	Laroia et al.	370/349
*	G	US-6,738,370 B2	05-2004	Ostman, Kjell	370/349
*	H	US-6,807,426 B2	10-2004	Pankaj, Rajesh K.	455/453
*	I	US-6,400,695 B1	06-2002	Chuah et al.	370/310
*	J	US-6,804,206 B1	10-2004	Moulsley, Timothy J.	370/320
*	K	US-6,868,079 B1	03-2005	Hunt, Bernard	370/345
*	L	US-6,961,570	11-2005	Kuo et al.	455/436
*	M	US-2004/0038681	02-2004	Chun, Chang-Hyen	455/436

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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	S					
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		Examiner Nick Deichmeister	Art Unit 2616	Page 2 of 2

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-2005/0175034	08-2005	De Jong et al.	370/473
*	B US-2005/0175033	08-2005	Funnell et al.	370/469
*	C US-2003/0207702	11-2003	Chen, Huan-Yueh	455/574
*	D US-2005/0054298	03-2005	Chen, Rex Huan-Yueh	455/067.11
*	E US-2004/0203623	10-2004	Wu, Frank Chih-Hsiang	455/412.1
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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